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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/786,703	02/24/2004	Chih-Feng Huang	JCLA12969	3675
75	90 10/05/2004		EXAMINER	
J.C. Patents, Ir Suite 250	nc.		QUINTO, KEVIN V	
4 Venture			ART UNIT	PAPER NUMBER
Irvine, CA 92	618		2826	
			DATE MAILED: 10/05/200	4

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)				
	10/786,703	HUANG ET AL.				
Office Action Summary	Examiner	Art Unit				
	Kevin Quinto	2826				
The MAILING DATE of this communication a Period for Reply	appears on the cover sheet w	ith the correspondence addr	ess			
A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a ref - If NO period for reply is specified above, the maximum statutory perion - Failure to reply within the set or extended period for reply will, by state that the period for reply will, by state that the material patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a reply within the statutory minimum of thir od will apply and will expire SIX (6) MON tute, cause the application to become Al	reply be timely filed ty (30) days will be considered timely. NTHS from the mailing date of this comments BANDONED (35 U.S.C. § 133).	munication.			
Status		•				
1) Responsive to communication(s) filed on 24	February 2004.					
	his action is non-final.					
3) Since this application is in condition for allow	_					
Disposition of Claims						
 4) ☐ Claim(s) 1-5 is/are pending in the application 4a) Of the above claim(s) is/are withd 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-5 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and 	rawn from consideration.					
Application Papers						
9)☐ The specification is objected to by the Exami	ner.					
0) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.						
Applicant may not request that any objection to the	ne drawing(s) be held in abeya	nce. See 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
	Examiner. Note the attached	d Office Action of form PTO	- 132.			
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for forei a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the priority application from the International Bure * See the attached detailed Office action for a li	ents have been received. ents have been received in A riority documents have been eau (PCT Rule 17.2(a)).	application No received in this National St	age			
Attachment(s)		,				
) Notice of References Cited (PTO-892)	4) Interview S	Summary (PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail Date nformal Patent Application (PTO-15	52)			
 Information Disclosure Statement(s) (PTO-1449 or PTO/SB/0 Paper No(s)/Mail Date 	6) Other;) '			

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DETAILED ACTION

Claim Rejections - 35 USC § 112

- The following is a quotation of the second paragraph of 35 U.S.C. 112:
 The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.
- 2. Claims 1-5 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.
- 3. Claim 1 uses the terms "extended drain region," "drain region," and "source region." However the specification does not disclose the amount of doping that the "extended drain region" or the "drain region" contains to differentiate it from the n-well and the n+ drain diffusion region. Furthermore the specification does not disclose the amount of doping that the "source region" contains to differentiate it from the n+ source diffusion region. Therefore the metes and bounds of "extended drain region," "drain region," and "source region" are unclear to the examiner. The examiner has interpreted the "extended drain region," "drain region," and the "source region," as having the same concentration as the n-well, thus making these regions indistinguishable (concentration-wise) from the rest of the n-well.
- 4. Claim 4 recites the limitation "said drain metal contact" in line 2 and "said source metal contact" in line 3. There is insufficient antecedent basis for these limitations in the claim.

5. The examiner believes that this claim was intended to be dependent on claim 3 and not claim 1 but is not certain. Thus the metes and bounds of claim 4 are unclear.

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Claim Rejections - 35 USC § 103

- 6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 7. Claims 1, 2, and 5 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tsui et al., "Integration of power LDMOS into low-voltage 0.5 µm BiCMOS technology," International Electron Devices Meeting, 1992. Technical Digest, p.27-30, in view of Hossain et al. (US 6,448,625 B1).
- 8. So far as understood in claims 1 and 5, Tsui et al., "Integration of power LDMOS into low-voltage 0.5 µm BiCMOS technology," International Electron Devices Meeting, 1992, Technical Digest, p.27-30 (hereinafter referred to as the "Tsui" reference), discloses a similar device. Figure 1 (the top left figure labeled "LDMOS" on p.29) of Tsui discloses a transistor with an n-well. The examiner notes the applicant has used the terms "first diffusion." "second diffusion." and "fourth diffusion" to describe how the n-well and isolated p-well are fabricated. However this places claim 1 into the form of a product-by-process claim:

Note that a "product by process" claim is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17 (footnote 3). See also In re Thorpe, 227 Application/Control Number: 10/786,703

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USPQ 964, 966; In re Luck, 177 USPQ 523; In re Fessmann, 180 USPQ 324; In re Avery, 186 USPQ 161; In re Wertheim, 191 USPQ 90 (209 USPQ 554 does not deal with this issue); and In re Marosi et al., 218 USPQ 289, all of which make it clear that it is the patentability of the final product per se which must be determined in a "product by process" claim, and not the patentability of the process, and that an old or obvious product produced by a new method is not patentable as a product, whether claimed in " product by process" claims or not. Note that applicant has the burden of proof in such cases, as the above case law makes clear. See also MPEP 2113.

Claim 1 does not distinguish over the Tsui reference regardless of the process used to form the n-well or isolated p-well, because only the final product is relevant, and not the process of making such as using two diffusion regions to form an n-well or a fourth diffusion to form an isolated p-well. There is a drain diffusion region containing N+ conductivity-type ions. There is a source diffusion region having N+ conductivity-type ions, forming a source region in the n-well. A channel is formed between the source and the drain region. A polysilicon gate electrode is formed over the channel to control a current flow in the channel. There is a contact diffusion region containing P+ conductivity-type ions, forming a contact region in the n-well. There is an isolated p-well or p body region formed in the n-well. The isolated p-well encloses the source region and the contact region. Tsui does not disclose the use of p-field regions in the n-well region. However the use of such regions is well known in the art. Hossain et al. (US 6,448,625 B1, hereinafter referred to as the "Hossain" reference) discloses the use of p-field regions (108) in figure 3C. Figure 3C of Hossain shows that there are several p-fields (108); some of which are closer to the drain (106) relative to other p-fields (108) on the left side of the figure. These p-fields generate junction fields in the n-well to deplete a drift region (column 2, lines 58-60). Hossain states that using these regions has the benefit of increasing the breakdown

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voltage (column 2, lines 60-61). Furthermore Hossain states that a high breakdown voltage is desirable (column 1, lines 11-13). In view of Hossain, it would therefore be obvious to use p-field regions in the device of Tsui.

9. So far as understood in claim 2, the n-well provides a low-impedance path for the source region and restricts a transistor current flow in between the drain region and the source region.

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Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kevin Quinto whose telephone number is (571) 272-1920. The examiner can normally be reached on M-F 8AM-5PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on (571) 272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

KVQ

